

**Data collection**

Siemens SMART CCD area-detector diffractometer 2555 reflections with  $I > 2\sigma(I)$   
 $\omega$  scans  $R_{\text{int}} = 0.072$   
 Absorption correction: empirical (SADABS); Sheldrick, 1996)  $\theta_{\text{max}} = 28.28^\circ$   
 $T_{\text{min}} = 0.913$ ,  $T_{\text{max}} = 0.983$   $h = -7 \rightarrow 7$   
 11 799 measured reflections  $k = -22 \rightarrow 37$   
 3688 independent reflections  $l = -13 \rightarrow 12$

**Refinement**

Refinement on  $F^2$   $w = 1/[\sigma^2(F_o^2) + (0.0958P)^2]$   
 $R[F^2 > 2\sigma(F^2)] = 0.053$  where  $P = (F_o^2 + 2F_c^2)/3$   
 $wR(F^2) = 0.165$   $(\Delta/\sigma)_{\text{max}} < 0.001$   
 $S = 1.056$   $\Delta\rho_{\text{max}} = 0.314 \text{ e } \text{\AA}^{-3}$   
 3688 reflections  $\Delta\rho_{\text{min}} = -0.396 \text{ e } \text{\AA}^{-3}$   
 221 parameters Extinction correction: none  
 H atoms treated by a mixture of independent and constrained refinement Scattering factors from *International Tables for Crystallography* (Vol. C)

Table 3. Selected geometric parameters ( $\text{\AA}$ ,  $^\circ$ ) for (II)

S1—C8	1.667 (2)	N1—C8	1.391 (2)
O1—C7	1.233 (2)	N2—C8	1.330 (2)
N1—C7	1.380 (2)	N2—C9	1.423 (2)
C7—N1—C8	128.2 (2)	O1—C7—C1	121.7 (2)
C8—N2—C9	127.9 (2)	N2—C8—N1	115.6 (2)

Table 4. Hydrogen-bonding geometry ( $\text{\AA}$ ,  $^\circ$ ) for (II)

D—H...A	D—H	H...A	D...A	D—H...A
N2—H1N2...O1	0.80 (2)	1.92 (2)	2.619 (2)	145 (2)
C10—H10...S1	0.95 (2)	2.85 (2)	3.253 (2)	107 (2)
N1—H1N1...S1 <sup>†</sup>	0.83 (2)	2.70 (2)	3.501 (2)	163 (3)

Symmetry code: (i)  $1 - x, 1 - y, 2 - z$ .

For both compounds, data collection: SMART (Siemens, 1996a); cell refinement: SAINT (Siemens, 1996b); data reduction: SAINT; program(s) used to solve structures: SHELXTL (Sheldrick, 1997); program(s) used to refine structures: SHELXTL; molecular graphics: SHELXTL; software used to prepare material for publication: SHELXTL and PARST (Nardelli, 1995).

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## The first mixed iodide–dithiocarbamate complex of selenium(II): catena-poly[[*(di-n-propyldithiocarbamato-S,S')*selenium(II)]- $\mu$ -iodo]

S. RAJASHREE,<sup>a</sup> R. KRISHNA KUMAR,<sup>a</sup>  
 G. ARAVAMUDAN,<sup>a</sup> M. R. UDUPA,<sup>a</sup> KANDASAMY  
 SIVAKUMAR<sup>b</sup>† AND HOONG-KUN FUN<sup>b</sup>

<sup>a</sup>Department of Chemistry, Indian Institute of Technology, Chennai 600 036, India, and <sup>b</sup>X-ray Crystallography Unit, School of Physics, Universiti Sains Malaysia, 11800 USM, Penang, Malaysia. E-mail: kramanat@unity.ncsu.edu

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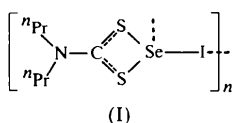
**Abstract**

The title compound, [SeI(C<sub>7</sub>H<sub>14</sub>NS<sub>2</sub>)<sub>n</sub>], was prepared by the oxidative displacement of one of the dithiocarbamates in bis(*di-n-propyldithiocarbamato*)-selenium(II) using iodine. This complex has a polymeric structure, with the central Se atoms bridged by the iodine ions. The geometry around each Se atom is planar trapezoidal (SeS<sub>2</sub>I<sub>2</sub>), with Se—I distances of 3.124 (2) and 3.232 (1) Å. This is the first example of a mixed iodide–dithiocarbamate complex of selenium(II).

† On leave from the Department of Physics, Anna University, Chennai 600 052, India.

### Comment

The title compound, (I), was prepared as part of studies on the complexes of selenium in the +II oxidation state and of tellurium in the +II and +IV oxidation states (Rajashree *et al.*, 1996; Krishna Kumar *et al.*, 1993a; Krishna Kumar, Aravamudan, Udupa, Seshasayee, Selvam & Yvon, 1996). Iodine reacts with dithiocarbamate complexes of selenium(II) and tellurium(II,IV) in two different ways. It oxidatively adds to tellurium in Te<sup>II</sup> complexes (Krishna Kumar, Aravamudan, Udupa, Seshasayee, Selvam & Yvon, 1996); however, with Te<sup>IV</sup>-dithiocarbamate complexes, it oxidatively displaces the dithiocarbamate (Krishna Kumar *et al.*, 1993b). The present studies confirm that in an Se<sup>II</sup>-dithiocarbamate complex, oxidative displacement occurs, resulting in the formation of iodo(di-*n*-propyldithiocarbamato)selenium(II), which is an interesting result, given that iodide is a good reducing agent for selenium(II) in aqueous solutions.



The structure determination of the title compound (Fig. 1) shows that it is analogous to TeLX (*L* = dithiocarbamate, X = I, Br, Cl; Krishna Kumar *et al.*, 1993a; Krishna Kumar, Aravamudan, Udupa & Seshasayee, 1996) and Se(Se<sub>2</sub>CNC<sub>4</sub>H<sub>8</sub>O)I (Bigoli *et al.*, 1983). As a discrete molecular species, selenium in the title complex would have only three coordinating atoms. Since selenium(II) prefers four-coordination, it resorts to supramolecular interactions through the iodide, giving a polymeric structure. These polymers are helical in nature and there are two such chains in the unit cell, running parallel to the [100] direction.

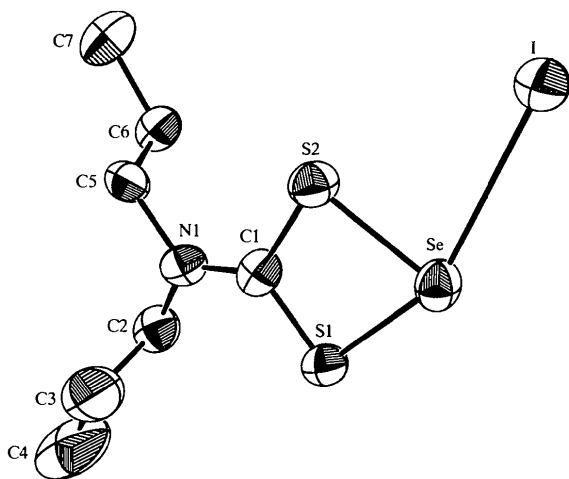


Fig. 1. The molecular structure of (I) shown with 50% probability displacement ellipsoids. H atoms have been omitted for clarity.

The asymmetric unit is composed of one iodide and one dithiocarbamate ligand coordinated to selenium. There are two different iodides bound to selenium, one is intramolecular and the other intermolecular; the distances are Se—I = 3.124 (2) and Se—I<sup>i</sup> = 3.232 (1) Å [symmetry code: (i)  $\frac{1}{2} + x, \frac{3}{2} - y, 1 - z$ ], which are longer than the sum of the covalent radii of the individual atoms, and the I—Se—I angle is 130.11 (4)°. The dithiocarbamate moiety is coordinated in an isobidentate fashion, the two Se—S distances being 2.298 (3) and 2.277 (3) Å. The angle made by the two S atoms with selenium is 76.84 (11)° and the resulting coordination geometry around selenium is planar trapezoidal. The distance between adjacent Se atoms within a chain is 4.158 (2) Å.

All other geometrical data pertaining to the dithiocarbamate ligand are similar to those observed in numerous previously determined structures. Atoms C3 and C4 are partially disordered, which is an expected phenomenon associated with alkyl groups.

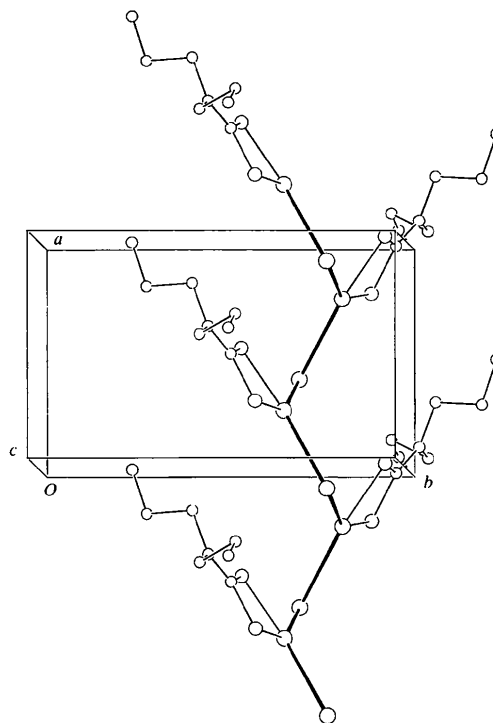


Fig. 2. A packing diagram showing the polymeric chain propagating along [100].

### Experimental

A solution (10 ml) of Se(dnpdctc)<sub>2</sub> (0.5 mmol; dnpdctc is di-*n*-propyldithiocarbamate) in CCl<sub>4</sub> was added to iodine (0.5 mmol, 0.125 g) dissolved in CCl<sub>4</sub> (20 ml). The resulting red solution gave a red crystalline product on solvent evaporation at low temperature. The excess iodine and the disulfide

formed were removed by repeated washing with CCl<sub>4</sub>. The yield of the complex was 0.180 g. Analysis found: C 21.87, H 3.68, N 3.60, Se 20.6, I 32.5%; calculated: C 21.87, H 3.69, N 3.66, Se 20.66, I 33.21%.

#### Crystal data

[SeI(C <sub>7</sub> H <sub>14</sub> NS <sub>2</sub> )]	Mo K $\alpha$ radiation
$M_r = 382.17$	$\lambda = 0.71069 \text{ \AA}$
Orthorhombic	Cell parameters from 36 reflections
$P2_12_12_1$	$\theta = 8-25^\circ$
$a = 6.905 (3) \text{ \AA}$	$\mu = 5.609 \text{ mm}^{-1}$
$b = 11.050 (6) \text{ \AA}$	$T = 293 (2) \text{ K}$
$c = 16.835 (2) \text{ \AA}$	Needle
$V = 1284.5 (9) \text{ \AA}^3$	$0.42 \times 0.12 \times 0.12 \text{ mm}$
$Z = 4$	Red-brown
$D_x = 1.976 \text{ Mg m}^{-3}$	
$D_m$ not measured	

#### Data collection

Siemens P4 diffractometer	1037 reflections with $I > 2\sigma(I)$
$\theta$ -2 $\theta$ scans	$\theta_{\max} = 24.97^\circ$
Absorption correction: $\psi$ scan (XSCANS; Siemens, 1994)	$h = 0 \rightarrow 8$
$T_{\min} = 0.374, T_{\max} = 0.510$	$k = 0 \rightarrow 13$
1279 measured reflections	$l = 0 \rightarrow 20$
1279 independent reflections	3 standard reflections every 97 reflections
	intensity decay: none

#### Refinement

Refinement on $F^2$	$(\Delta/\sigma)_{\max} < 0.001$
$R[F^2 > 2\sigma(F^2)] = 0.035$	$\Delta\rho_{\max} = 0.392 \text{ e \AA}^{-3}$
$wR(F^2) = 0.094$	$\Delta\rho_{\min} = -0.513 \text{ e \AA}^{-3}$
$S = 1.092$	Extinction correction: none
1279 reflections	Scattering factors from <i>International Tables for Crystallography</i> (Vol. C)
109 parameters	Absolute structure: Flack (1983)
H atoms were fixed geometrically and refined using a riding model	Flack parameter = 0.00 (4)
$w = 1/[\sigma^2(F_o^2) + (0.0496P)^2 + 1.4891P]$	
where $P = (F_o^2 + 2F_c^2)/3$	

Table 1. Selected geometric parameters ( $\text{\AA}$ ,  $^\circ$ )

I—Se	3.124 (2)	Se—I <sup>i</sup>	3.232 (1)
Se—S2	2.277 (3)	S1—C1	1.729 (11)
Se—S1	2.298 (3)	S2—C1	1.725 (11)
S2—Se—S1	76.84 (11)	C1—S1—Se	85.8 (4)
S2—Se—I	77.66 (8)	C1—S2—Se	86.5 (4)
S1—Se—I <sup>i</sup>	75.23 (8)	S2—C1—S1	110.8 (6)
I—Se—I <sup>i</sup>	130.11 (4)		

Symmetry code: (i)  $\frac{1}{2} + x, \frac{3}{2} - y, 1 - z$ .

The disorder in atoms C3 and C4 could not be resolved satisfactorily by assigning partial sites.

Data collection: XSCANS (Siemens, 1994). Cell refinement: XSCANS. Data reduction: XSCANS. Program(s) used to solve structure: SHELXS86 (Sheldrick, 1985). Program(s) used to refine structure: SHELXL97 (Sheldrick, 1997). Molecular graphics: ORTEPII (Johnson, 1976). Software used to prepare material for publication: SHELXL97.

Supplementary data for this paper are available from the IUCr electronic archives (Reference: GD1008). Services for accessing these data are described at the back of the journal.

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### (S)-8-Chloro-5-methyl-6-(3-methylbut-2-enyl)-2-thioxo-1H-4,5,6,7-tetrahydroimidazo[4,5,1-jk][1,4]benzodiazepinium bromide methanol solvate†

OSWALD M. PEETERS, NORBERT M. BLATON AND CAMIEL J. DE RANTER

Laboratorium voor Analytische Chemie en Medicinale Fysicochemie, Faculteit Farmaceutische Wetenschappen, Katholieke Universiteit Leuven, Van Evenstraat 4, B-3000 Leuven, Belgium. E-mail: maurice.peeters@farm.kuleuven.ac.be

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#### Abstract

The crystal structure of the title compound, C<sub>16</sub>H<sub>21</sub>ClN<sub>3</sub>S<sup>+</sup>·Br<sup>-</sup>·CH<sub>3</sub>OH, the hydrobromide salt of (S)-8-Cl-TIBO (tivirapine), reveals a distorted boat–sofa conformation for the diazepine ring, with the methyl group and the 3-methylbut-2-enyl side chain in equatorial and axial positions, respectively. The protonated N atom has

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